

Notice of References Cited	Application/Control No. 10/552,088		Applicant(s)/Patent Under Reexamination YOON ET AL.	
	Examiner TAI DUONG		Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0011739	01-2003	Yoshihara et al.	349/172
*	B	US-2002/0057253	05-2002	Lim et al.	345/102
*	C	US-6,727,966	04-2004	Tanaka, Tomio	349/114
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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